

OptiMOS™-T2 Power-Transistor

AEC® ® Qualified



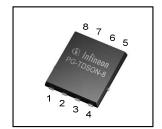
Features

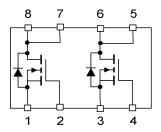
- Dual N-channel Logic Level Enhancement mode
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested

Product Summary

$V_{ m DS}$	100	V
$R_{\mathrm{DS(on),max}}^{4)}$	22	mΩ
I _D	20	Α

PG-TDSON-8-4





Туре	Package	Marking
IPG20N10S4L-22	PG-TDSON-8-4	4N10L22

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current one channel active ¹⁾	I _D	T _C =25°C, V _{GS} =10V	20	A
		$T_{\rm C}$ =100°C, $V_{\rm GS}$ =10 $V^{2)}$	20	
Pulsed drain current ²⁾ one channel active	I _{D,pulse}	-	80	
Avalanche energy, single pulse ^{2, 4)}	E _{AS}	/ _D =10A	130	mJ
Avalanche current, single pulse ⁴⁾	IAS	-	15	А
Gate source voltage	V_{GS}	-	±16	V
Power dissipation one channel active	P_{tot}	T _C =25°C	60	w
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 + 175	°C



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	2.5	K/W
SMD version, device on PCB	R_{thJA}	minimal footprint	-	100	-	
		6cm ² cooling area ³⁾	-	60	-	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{\rm GS}$ =0V, $I_{\rm D}$ = 1mA	100	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}$, $I_{\rm D} = 25 \mu A$	1.1	1.6	2.1	1
Zero gate voltage drain current ⁴⁾	I _{DSS}	$V_{\rm DS}$ =100V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C	-	0.01	1	μΑ
		$V_{\rm DS}$ =100V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C ²⁾	-	1	100	
Gate-source leakage current ⁴⁾	I _{GSS}	V _{GS} =16V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance ⁴⁾	$R_{\mathrm{DS(on)}}$	V _{GS} =4.5V, I _D =10A	1	24	28	mΩ
		V _{GS} =10V, I _D =17A	-	20	22	



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance ⁴⁾	Ciss		-	1350	1755	pF
Output capacitance ⁴⁾	Coss	$V_{\rm GS}$ =0V, $V_{\rm DS}$ =25V, f =1MHz	-	450	585	
Reverse transfer capacitance ⁴⁾	C _{rss}		-	42	84	
Turn-on delay time	$t_{d(on)}$		-	5	-	ns
Rise time	t_{r}	V _{DD} =50V, V _{GS} =10V,	-	3	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =20A, $R_{\rm G}$ =11 Ω	-	30	-	
Fall time	t_{f}		-	18	-	
Gate Charge Characteristics ^{2, 4)}						
Gate to source charge	Q _{gs}		-	4.3	5.6	nC
Gate to drain charge	Q _{gd}	V _{DD} =80V, I _D =20A,	-	4.8	9.6	
Gate charge total	Qg	V _{GS} =0 to 10V	-	21	27	
Gate plateau voltage	V _{plateau}		-	3.2	-	V
Reverse Diode						
Diode continous forward current ²⁾ one channel active	Is		-	-	20	А
Diode pulse current ²⁾ one channel active	I _{S,pulse}	-T _C =25°C	-	-	80	
Diode forward voltage	V_{SD}	V _{GS} =0V, I _F =17A, T _j =25°C	-	1.0	1.3	V
Reverse recovery time ²⁾	t _{rr}	V_{R} =50V, I_{F} = I_{S} , di_{F}/dt =100A/ μ s	-	55	-	ns
Reverse recovery charge ^{2, 4)}	Q _{rr}		-	100	-	nC

¹⁾ Current is limited by bondwire; with an $R_{\rm thJC}$ = 2.5K/W the chip is able to carry 36A at 25°C.

²⁾ Specified by design. Not subject to production test.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

⁴⁾ Per channel

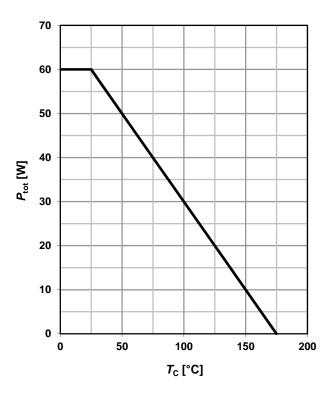


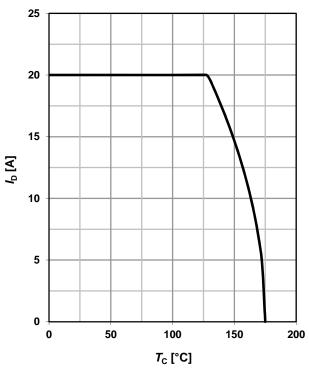
1 Power dissipation

 P_{tot} =f(T_{C}); $V_{\text{GS}} \ge 6V$; one channel active

2 Drain current

 $I_D = f(T_C)$; $V_{GS} \ge 6V$; one channel active





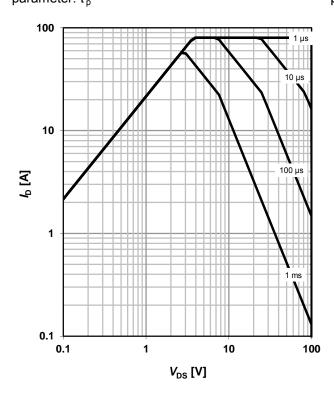
3 Safe operating area

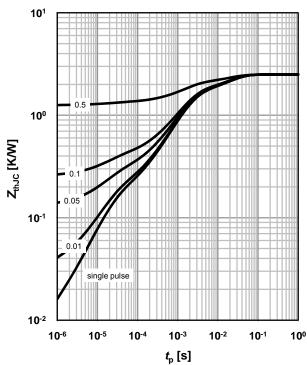
 $I_{\rm D}$ =f($V_{\rm DS}$); $T_{\rm C}$ =25°C; D=0; one channel active parameter: $t_{\rm p}$

4 Max. transient thermal impedance

 $Z_{\rm thJC}$ =f($t_{\rm p}$)

parameter: $D=t_p/T$



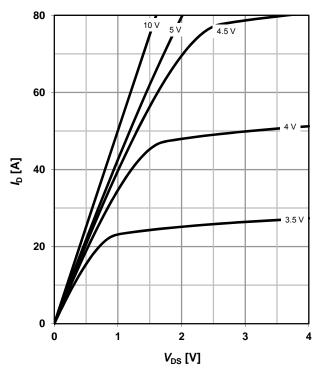




5 Typ. output characteristics⁵⁾

 $I_D = f(V_{DS}); T_i = 25^{\circ}C$

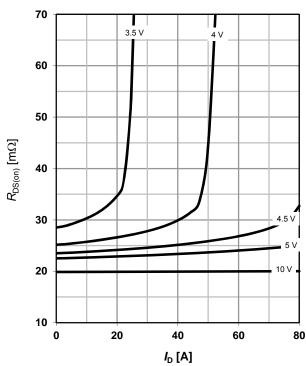
parameter: V_{GS}



6 Typ. drain-source on-state resistance⁵⁾

 $R_{DS(on)}$ =f(I_D); T_j =25°C

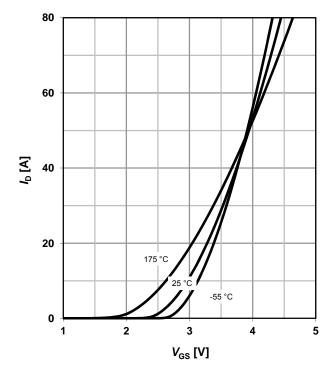
parameter: V_{GS}



7 Typ. transfer characteristics⁵⁾

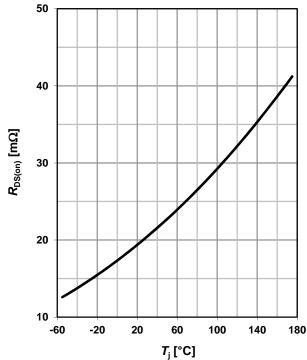
 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: T_i



8 Typ. drain-source on-state resistance⁵⁾

 $R_{DS(on)}$ =f(T_j); I_D =17A; V_{GS} =10V





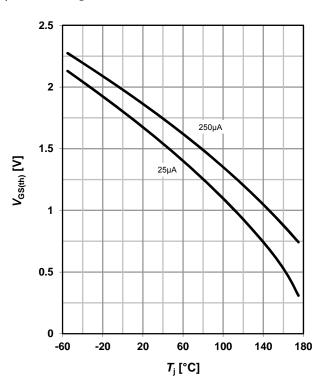
9 Typ. gate threshold voltage

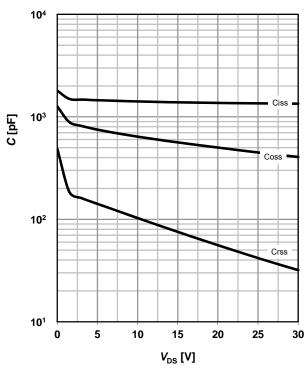
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. Capacitances⁵⁾

 $C=f(V_{DS}); V_{GS}=0V; f=1MHz$





11 Typical forward diode characteristicis⁵⁾

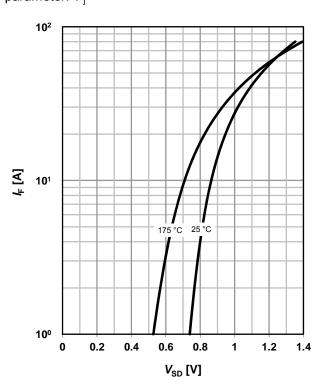
 $I_F = f(V_{SD})$

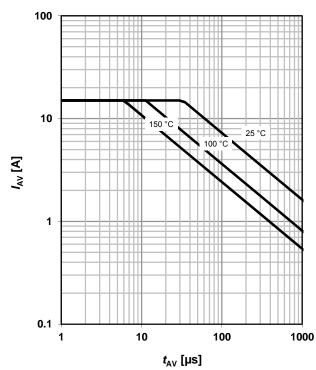
parameter: T_i

12 Avalanche characteristics⁵⁾

 I_{AS} =f (t_{AV})

parameter: T_{i(start)}





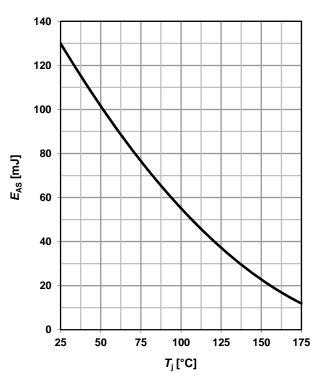


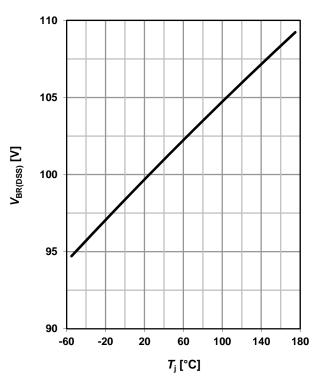
13 Avalanche energy⁵⁾

 $E_{AS}=f(T_i), I_D=10A$

14 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f(T_j); I_D =1mA

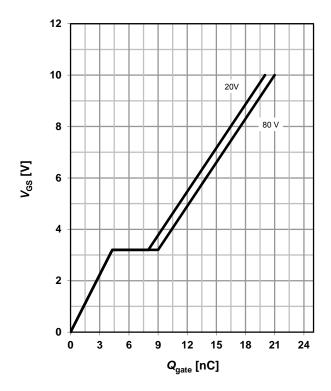




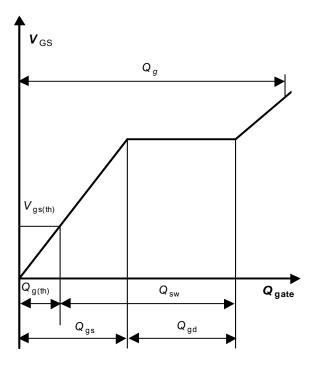
15 Typ. gate charge⁵⁾

 $V_{\rm GS}$ =f(Q_{gate}); $I_{\rm D}$ =20A pulsed

parameter: $V_{\rm DD}$



16 Gate charge waveforms





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Revision History

Version	Date	Changes
Revision 1.0	29.11.2011	Final Data Sheet
Revision 1.1	30.01.2013	Updte of marking